

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: OKUDA, Yuichi  
Serial No.: Not yet assigned  
Filed: January 30, 2004  
For: SEMICONDUCTOR MEMORY DEVICE AND TEST METHOD

**INFORMATION DISCLOSURE STATEMENT**  
**UNDER 37 CFR 1.97 & 1.98**

Mail Stop DD  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

January 30, 2004

Sir:

In the matter of the above-identified application, applicants are submitting herewith a copy of the documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

This information disclosure statement is being submitted with the new application.

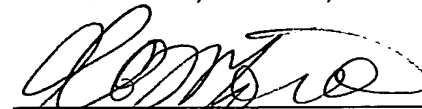
Although one of the documents listed on the attached form equivalent to Form PTO-1449 is not in the English language, the requirement of 37 CFR 1.98(a)(3) for a concise explanation of the relevance is satisfied by the discussion of the document in the specification, for example, on page one (1).

It is respectfully requested that this information disclosure statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to the deposit account of Antonelli, Terry, Stout & Kraus Deposit Account No. 01-2135 (Case: 501.43354X00), and please credit any excess fees to such deposit account.

Respectfully submitted,

ANTONELLI, TERRY, STOUT & KRAUS LLP



---

Gregory E. Montone  
Registration No. 28,141

GEM/alb  
(703) 312-6600  
Attachments

<b>Form PTO-1449</b>	<b>U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</b>	<b>ATTY. DKT. NO.</b> 501.43354X00	<b>SERIAL NO.</b>
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use several sheets if necessary)		<b>APPLICANT</b> OKUDA, Yuichi	
		<b>FILING DATE</b> January 30, 2004	<b>GROUP</b>

**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
AA	6,295,617	09/25/2001	SONOBE	714	718	06/30/1998
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						
AL						

**FOREIGN PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Country	Class	Subclass	Abstract	
						Yes	No
AM	11-25689	01/29/1999	JP	G11C	29/00		X
AN							
AO							
AP							
AQ							
AR							
AS							
AT							

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

	AU	
	AV	
	AW	
	AX	
	AY	
	AZ	
<b>Examiner</b>		<b>Date Considered</b>